## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination SAWAI ET AL. | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,839,642	01-2005	Kawakita et al.	702/42
	В	US-			
	O	US-			
	D	US-			
	Ε	US-			
	۴	US-			
	G	US-			
	Н	US-			
	-	US-			
	J	US-			
	К	US-			
	L	US-			,
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р				·	
	Q					
·	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Morita et al., "Numerical Model of Crimping by Finite Element Analysis" 1996 IEEE pg. 16-20.
	٧	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.